SUMMARY OF TOPICS

Areas covered in PAACB Spore Analyst Level I exams.

Topics not covered under this outline may be covered on the PAACB exams if determined to be appropriate by the PAACB Scientific Committee; this is not necessarily a comprehensive or detailed list of topics with which an analyst should be familiar.

Guidance Document #1: Basic Background Knowledge

- I. Basic mycology
 - A. Basic taxonomy

1.-3. Basic taxonomy; Familiarity with major groups producing airborne fungi (Oomycetes, Zygomycetes, Ascomycetes, Basidiomycetes, Deuteromycetes);

- 4. Understand the concept of Latin binomials.
- B. Mechanisms of spore production and release.

1. Understand how spore production relates to morphology among the major fungal groups.

- 2. Relate spore release with weather parameters
- C. Spore morphology
- II. Basic knowledge of bioaerosols
 - B. Basic understanding of particle settling, impaction, and filtration.
 - C. Know how to calculate concentrations from raw particle counts.
 - D. Basic understanding of the characteristics and patterns of spore prevalence (e.g, seasonality, frequency of recovery)
- V. Air sampling methods

A.1.-3. Have a working knowledge of the various samplers designed for direct microscopic examination.

Guidance Document #2: Bioaerosol Sampling

- II. Sampler descriptions
 - A. Basic knowledge of samplers designed for direct microscopic examination.
- III. Microscopy
 - A. Familiarity with the microscope
 - B. Familiarity with Köhler (or "even") illumination.
 - C.-D. Know how to measure the field of view and calibrate an eyepiece micrometer.
- IV. Data
 - A. Calculations
 - 1. Be able to determine particles per sample (if only a fraction is counted)
 - 2. Be able to calculate airborne concentrations (particles/m3) from raw counts.

Guidance Document #3: Specific Protocols

- I. Acceptable samples
 - A. Know how a slide should be labeled.
 - B. Know how to best analyze a broken or damaged sample.
- II. Know how to prepare a sample for direct microscopic examination.
- IV. Approaches to sample analysis

A. Basic knowledge of particle deposition variability and approaches to counting a representative portion of a sample.

B. Understand approaches to dealing with overloaded samples.